

L Number	Hits	Search Text	DB	Time stamp
9	23282	measur\$3 with intensity	EPO; JPO; DERWENT	2003/03/14 13:45
10	144	coefficient with (chang\$ with parameter)	EPO; JPO; DERWENT	2003/03/14 13:45
11	38639	measur\$3 with intensity	USPAT; US-PGPUB	2003/03/14 13:45
12	368	coefficient with (chang\$ with parameter)	USPAT; US-PGPUB	2003/03/14 13:46
13	0	(measur\$3 with intensity) and (coefficient with (chang\$ with parameter))	EPO; JPO; DERWENT	2003/03/14 13:46
14	4640	coefficient with parameter	USPAT; US-PGPUB	2003/03/14 13:46
15	222	(measur\$3 with intensity) and (coefficient with parameter)	USPAT; US-PGPUB	2003/03/14 13:46
16	396348	semiconductor or "integrated circuit"	USPAT; US-PGPUB	2003/03/14 13:48
17	303677	@ad>20010216 or @rlad>20010216	USPAT; US-PGPUB	2003/03/14 13:48
18	73	((measur\$3 with intensity) and (coefficient with parameter)) and (semiconductor or "integrated circuit")	USPAT; US-PGPUB	2003/03/14 13:48
19	56	((measur\$3 with intensity) and (coefficient with parameter)) and (semiconductor or "integrated circuit")) not (@ad>20010216 or @rlad>20010216)	USPAT; US-PGPUB	2003/03/14 14:09
20	1	("6327035").PN.	USPAT; US-PGPUB	2003/03/14 14:09
-	536	438/16.ccls.	USPAT; US-PGPUB	2003/03/04 12:56
-	1	((beam or electromagnetic) and (sidewall and (opening or groove or hole or trench)) and (measur\$3 with intensity) and 438/16.ccls.) not (@ad>20010216 or @rlad>20010216)	USPAT; US-PGPUB	2003/03/04 12:56
-	4	(beam or electromagnetic) and (sidewall and (opening or groove or hole or trench)) and (measur\$3 with intensity) and 438/16.ccls.	USPAT; US-PGPUB	2003/03/04 13:25
-	8	(sidewall and (opening or groove or hole or trench)) and (measur\$3 with intensity) and 438/16.ccls.	USPAT; US-PGPUB	2003/03/04 13:01
-	4	((sidewall and (opening or groove or hole or trench)) and (measur\$3 with intensity) and 438/16.ccls.) not (@ad>20010216 or @rlad>20010216)	USPAT; US-PGPUB	2003/03/04 13:01
-	71	(beam or electromagnetic) and (measur\$3 with intensity) and 438/16.ccls.	USPAT; US-PGPUB	2003/03/04 13:03
-	54	((beam or electromagnetic) and (measur\$3 with intensity) and 438/16.ccls.) not (@ad>20010216 or @rlad>20010216)	USPAT; US-PGPUB	2003/03/04 13:25
-	988	438/14.ccls.	USPAT; US-PGPUB	2003/03/04 13:25
-	9	(beam or electromagnetic) and (sidewall and (opening or groove or hole or trench)) and (measur\$3 with intensity) and 438/14.ccls.	USPAT; US-PGPUB	2003/03/04 13:26
-	1	((beam or electromagnetic) and (sidewall and (opening or groove or hole or trench)) and (measur\$3 with intensity) and 438/14.ccls.) not (@ad>20010216 or @rlad>20010216)	USPAT; US-PGPUB	2003/03/04 13:25
-	48	(beam or electromagnetic) and (measur\$3 with intensity) and 438/14.ccls.	USPAT; US-PGPUB	2003/03/04 13:26
-	21	((beam or electromagnetic) and (measur\$3 with intensity) and 438/14.ccls.) not (@ad>20010216 or @rlad>20010216)	USPAT; US-PGPUB	2003/03/04 13:26
-	1380	438/for.142.ccls.	EPO; JPO; DERWENT	2003/03/04 13:30
-	699420	beam or electromagnetic	EPO; JPO; DERWENT	2003/03/04 13:30
-	15796	sidewall and (opening or groove or hole or trench)	EPO; JPO; DERWENT	2003/03/04 13:30
-	1	(beam or electromagnetic) and (sidewall and (opening or groove or hole or trench)) and (measur\$3 with intensity)	EPO; JPO; DERWENT	2003/03/04 13:31
-	0	438/for.142.ccls. and (sidewall and (opening or groove or hole or trench)) and (measur\$3 with intensity)	EPO; JPO; DERWENT	2003/03/04 13:31

-	6	438/for.142.ccls. and (beam or electromagnetic) and (measur\$3 with intensity)	EPO; JPO; DERWENT	2003/03/04 13:33
-	0	438/for.142.ccls. and (estrada.xa. and angel)	EPO; JPO; DERWENT	2003/03/04 13:33
-	0	(sidewall and (opening or groove or hole or trench)) and (438/for.142.ccls. and (beam or electromagnetic))	EPO; JPO; DERWENT	2003/03/04 13:34
-	176	438/for.142.ccls. and (beam or electromagnetic)	EPO; JPO; DERWENT	2003/03/04 13:34
-	29099	"electromagnetic radiation"	USPAT;	2003/03/13 14:32
-	78038	sidewall and (opening or groove or hole or trench)	US-PGPUB	2003/03/13 14:33
-	38639	measur\$3 with intensity	USPAT;	2003/03/13 14:34
-	51	"electromagnetic radiation" and (sidewall and (opening or groove or hole or trench)) and (measur\$3 with intensity)	US-PGPUB	2003/03/13 14:34
-	30	("electromagnetic radiation" and (sidewall and (opening or groove or hole or trench)) and (measur\$3 with intensity)) not (@ad>20010216 or @rlad>20010216)	USPAT;	2003/03/13 15:03
-	0	"probe light" with "electromagnetic radiation"	USPAT;	2003/03/13 14:40
-	1	"probe light" same "electromagnetic radiation"	US-PGPUB	2003/03/13 14:41
-	84	"probe light" and "electromagnetic radiation"	USPAT;	2003/03/13 14:42
-	303	reflective with ("silicon oxide" or "Si O.sub.2")	US-PGPUB	2003/03/13 15:06
-	17133	wavelength with thickness	USPAT;	2003/03/13 16:04
-	1636	(measur\$3 with intensity) and (wavelength with thickness)	US-PGPUB	2003/03/13 16:05
-	45	(sidewall and (opening or groove or hole or trench)) and ((measur\$3 with intensity) and (wavelength with thickness))	USPAT;	2003/03/13 16:05
-	16	((sidewall and (opening or groove or hole or trench)) and ((measur\$3 with intensity) and (wavelength with thickness))) not (@ad>20010216 or @rlad>20010216)	US-PGPUB	2003/03/13 16:05
-	68	(sidewall with opposite) with measur\$3	USPAT;	2003/03/14 11:14
-	492749	beam or electromagnetic	US-PGPUB	2003/03/14 11:44
-	11	((sidewall with opposite) with measur\$3) and (beam or electromagnetic)	USPAT;	2003/03/14 11:15
-	10	((sidewall with opposite) with measur\$3) and (beam or electromagnetic)) not (@ad>20010216 or @rlad>20010216)	US-PGPUB	2003/03/14 11:41
-	4	((sidewall with opposite) with measur\$3) and (semiconductor or "integrated circuit")	USPAT;	2003/03/14 11:42
-	3	((sidewall with opposite) with measur\$3) and (semiconductor or "integrated circuit")) not (@ad>20010216 or @rlad>20010216)	US-PGPUB	2003/03/14 11:43
-	1610	sidewall with measur\$3	USPAT;	2003/03/14 11:44
-	1269916	beam or electromagnetic or probe or light	US-PGPUB	2003/03/14 11:45
-	95	(sidewall with measur\$3) with (beam or electromagnetic or probe or light)	USPAT;	2003/03/14 11:45
-	25	(semiconductor or "integrated circuit") and ((sidewall with measur\$3) with (beam or electromagnetic or probe or light))	US-PGPUB	2003/03/14 11:46
-	22	((semiconductor or "integrated circuit") and ((sidewall with measur\$3) with (beam or electromagnetic or probe or light))) not (@ad>20010216 or @rlad>20010216)	USPAT;	2003/03/14 11:51
-	0	sidewall with measurements with parameteres	US-PGPUB	2003/03/14 11:52
-	0	sidewall same measurements with parameteres	USPAT;	2003/03/14 11:52
-	0	sidewall same (measurements with parameteres)	US-PGPUB	2003/03/14 11:52

-	0	sidewall same (measurements same parameteres)	USPAT; US-PGPUB	2003/03/14 11:52
-	1	(measurements with parameteres) and (beam or electromagnetic or probe or light)	USPAT; US-PGPUB	2003/03/14 11:53
-	1	(measurements same parameteres) and (beam or electromagnetic or probe or light)	USPAT; US-PGPUB	2003/03/14 11:54
-	0	(measurements near parameteres) and (beam or electromagnetic or probe or light)	USPAT; US-PGPUB	2003/03/14 11:54
-	14	(measurements and parameteres) and (beam or electromagnetic or probe or light)	USPAT; US-PGPUB	2003/03/14 11:54
-	38639	measur\$3 with intensity	USPAT; US-PGPUB	2003/03/14 11:55
-	1	((measurements and parameteres) and (beam or electromagnetic or probe or light)) and (measur\$3 with intensity)	USPAT; US-PGPUB	2003/03/14 11:55